



- (51) **International Patent Classification:**
H03L 7/00 (2006.01)
- (21) **International Application Number:**
PCT/IL2013/050926
- (22) **International Filing Date:**
11 November 2013 (11.11.2013)
- (25) **Filing Language:** English
- (26) **Publication Language:** English
- (30) **Priority Data:**
224819 20 February 2013 (20.02.2013) IL
- (71) **Applicant:** ISRAEL AEROSPACE INDUSTRIES LTD.
[IL/IL]; Ben-Gurion International Airport, 70100 Lod (IL).
- (72) **Inventors:** GREENBERG, Igal; 122 Derech Ramatayim,
4526023 Hod Hasharon (IL). LEVI, Raphael; 9 Menahem
Begin Boulevard, 5647805 Yahud (IL).
- (74) **Agent:** REINHOLD COHN AND PARTNERS; P.O.Box
13239, 6113102 Tel Aviv (IL).
- (81) **Designated States** (*unless otherwise indicated, for every
kind of national protection available*): AE, AG, AL, AM,

AO, AT, AU, AZ, BA, BB, BG, BH, BN, BR, BW, BY,
BZ, CA, CH, CL, CN, CO, CR, CU, CZ, DE, DK, DM,
DO, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, GT,
HN, HR, HU, ID, IL, IN, IR, IS, JP, KE, KG, KN, KP, KR,
KZ, LA, LC, LK, LR, LS, LT, LU, LY, MA, MD, ME,
MG, MK, MN, MW, MX, MY, MZ, NA, NG, NI, NO, NZ,
OM, PA, PE, PG, PH, PL, PT, QA, RO, RS, RU, RW, SA,
SC, SD, SE, SG, SK, SL, SM, ST, SV, SY, TH, TJ, TM,
TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, ZA, ZM,
ZW.

- (84) **Designated States** (*unless otherwise indicated, for every
kind of regional protection available*): ARIPO (BW, GH,
GM, KE, LR, LS, MW, MZ, NA, RW, SD, SL, SZ, TZ,
UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, RU, TJ,
TM), European (AL, AT, BE, BG, CH, CY, CZ, DE, DK,
EE, ES, FI, FR, GB, GR, HR, HU, IE, IS, IT, LT, LU, LV,
MC, MK, MT, NL, NO, PL, PT, RO, RS, SE, SI, SK, SM,
TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW,
KM, ML, MR, NE, SN, TD, TG).

Published:

— with international search report (Art. 21(3))

(54) **Title:** SYSTEM AND METHOD FOR TESTING FREQUENCY SYNTHESIZER

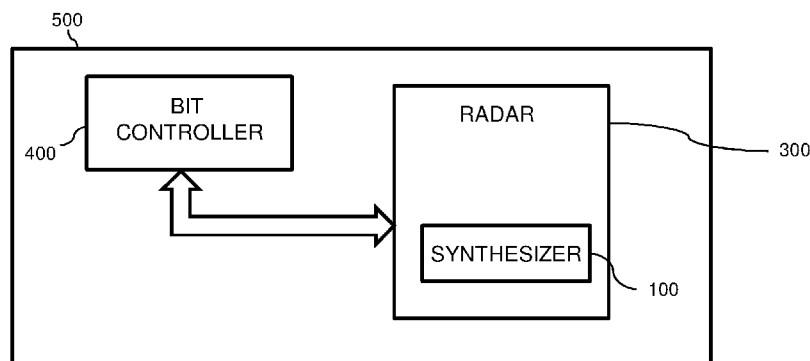


FIG. 1

(57) **Abstract:** A method of testing a frequency synthesizer over a predetermined frequency range using a delay unit complying with a spectral delay distribution model modeling a spectral delay distribution of the delay unit over the predetermined frequency range. The method comprises generating at least one test signal with the frequency synthesizer according to at least one test command; passing the at least one test signal through the delay unit so as to obtain at least one delayed test signal; measuring at least one shift of a signal attribute between the delayed test signal and the test signal; estimating an accuracy of the frequency synthesizer by comparing the at least one measured shift with an expected shift, the expected shift being derived from the spectral delay distribution model of the delay unit and from the at least one test command.